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Data Sheet

November 2013

600 V SMPS IGBT

The HGTG30N60A4 combines the best features of high input impedance of a MOSFET and the low on-state conduction loss of a bipolar transistor. This IGBT is ideal for many high voltage switching applications operating at high frequencies where low conduction losses are essential. This device has been optimized for fast switching applications.

Formerly Developmental Type TA49343.

Ordering Information

PART NUMBER	PACKAGE	BRAND	
HGTG30N60A4	TO-247	G30N60A4	

NOTE: When ordering, use the entire part number.

Features

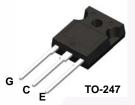
- 60 A, 600 V @ T_C = 110°C
- Low Saturation Voltage: V_{CE(sat)} = 1.8 V @ I_C = 30 A
- Typical Fall Time. 58ns at T_J = 125°C
- Low Conduction Loss

Applications

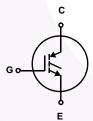
• UPS, Welder

Packaging

JEDEC STYLE TO-247



Symbol



FAIRC	HILD CORPORA	TION IGBT PROD	UCT IS COVERE	D BY ONE OR MO	RE OF THE FOLI	LOWING U.S. PAT	TENTS
4,364,073	4,417,385	4,430,792	4,443,931	4,466,176	4,516,143	4,532,534	4,587,713
4,598,461	4,605,948	4,620,211	4,631,564	4,639,754	4,639,762	4,641,162	4,644,637
4,682,195	4,684,413	4,694,313	4,717,679	4,743,952	4,783,690	4,794,432	4,801,986
4,803,533	4,809,045	4,809,047	4,810,665	4,823,176	4,837,606	4,860,080	4,883,767
4,888,627	4,890,143	4,901,127	4,904,609	4,933,740	4,963,951	4,969,027	

HGTG30N60A4

Absolute Maximum Ratings $T_C = 25^{\circ}C$, Unless Otherwise Specified

	Ratings	UNIT
Collector to Emitter Voltage	600	V
Collector Current Continuous		
At $T_C = 25^{\circ}C$ I_{C25}	75	Α
At T _C = 110°C	60	Α
Collector Current Pulsed (Note 1)	240	Α
Gate to Emitter Voltage Continuous	±20	V
Gate to Emitter Voltage Pulsed	±30	V
Switching Safe Operating Area at T _J = 150°C, Figure 2SSOA	150 A at 600 V	
Power Dissipation Total at T _C = 25°C	463	W
Power Dissipation Derating T _C > 25°C	3.7	W/oC
Operating and Storage Junction Temperature Range T _J , T _{STG}	-55 to 150	°C
Maximum Lead Temperature for Soldering		
Leads at 0.063in (1.6mm) from Case for 10sT _L	300	οС
Package Body for 10s, See Techbrief 334 T _{PKG}	260	°C

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE

1. Pulse width limited by maximum junction temperature.

Electrical Specifications $T_J = 25^{\circ}C$, Unless Otherwise Specified

PARAMETER	SYMBOL	TEST C	ONDITIONS	MIN	TYP	MAX	UNIT
Collector to Emitter Breakdown Voltage	BV _{CES}	$I_C = 250 \mu A, V_{GE} = 0 V$		600	-	-	V
Emitter to Collector Breakdown Voltage	BV _{ECS}	I_C = -10 mA, V_{GE}	= 0 V	20	-	-	V
Collector to Emitter Leakage Current	I _{CES}	V _{CE} = 600 V	$T_J = 25^{\circ}C$	-	-	250	μА
			$T_{J} = 125^{\circ}C$	- /	-	4.0	mA
Collector to Emitter Saturation Voltage	V _{CE(SAT)}	I _C = 30 A,	$T_J = 25^{\circ}C$	-	1.8	2.6	V
		V _{GE} = 15 V	$T_{J} = 125^{O}C$	-	1.6	2.0	V
Gate to Emitter Threshold Voltage	V _{GE(TH)}	I _C = 250 μA, V _{CE}	= 600 V	4.5	5.2	7.0	V
Gate to Emitter Leakage Current	I _{GES}	V _{GE} = ±20 V		-	-	±250	nA
Switching SOA	SSOA	$T_J = 150^{\circ}\text{C}, R_G = 3 \Omega, V_{GE} = 15 \text{ V}$ L = 100 $\mu\text{H}, V_{CE} = 600 \text{ V}$		150	-	-	Α
Gate to Emitter Plateau Voltage	V _{GEP}	I _C = 30 A, V _{CE} = 300 V		-	8.5	-	V
On-State Gate Charge	Q _{g(ON)}		V _{GE} = 15 V	-	225	270	nC
		V _{CE} = 300 V	V _{GE} = 20 V	-	300	360	nC
Current Turn-On Delay Time	t _{d(ON)I}	IGBT and Diode at $T_J = 25^{\circ}C$ $I_{CE} = 30 \text{ A}$ $V_{CE} = 390 \text{ V}$ $V_{GE} = 15 \text{ V}$ $R_G = 3 \Omega$ $L = 200 \mu H$ Test Circuit - (Figure 20)		-	25	-	ns
Current Rise Time	t _{rl}			-	12	-	ns
Current Turn-Off Delay Time	t _d (OFF)I			-	150	-	ns
Current Fall Time	t _{fl}			-	38	-	ns
Turn-On Energy (Note 2)	E _{ON1}			-	280	-	μJ
Turn-On Energy (Note 2)	E _{ON2}			-	600	-	μJ
Turn-Off Energy (Note 3)	E _{OFF}			-	240	350	μJ

HGTG30N60A4

Electrical Specifications $T_J = 25^{\circ}C$, Unless Otherwise Specified (Continued)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Current Turn-On Delay Time	t _d (ON)I	IGBT and Diode at T _J = 125°C	-	24	-	ns
Current Rise Time	t _{rl}	I _{CE} = 30 A V _{CE} = 390 V	-	11	-	ns
Current Turn-Off Delay Time	t _d (OFF)I	V _{GE} = 15 V	-	180	200	ns
Current Fall Time	t _{fl}	$R_G = 3 \Omega$ L = 200 μH	-	58	70	ns
Turn-On Energy (Note 2)	E _{ON1}	Test Circuit - (Figure 20)	-	280	-	μJ
Turn-On Energy (Note 2)	E _{ON2}		-	1000	1160	μJ
Turn-Off Energy (Note 3)	E _{OFF}		-	450	750	μJ
Thermal Resistance Junction To Case	$R_{ heta JC}$		-	-	0.27	oC/W

NOTES:

- Values for two Turn-On loss conditions are shown for the convenience of the circuit designer. E_{ON1} is the turn-on loss of the IGBT only. E_{ON2} is the turn-on loss when a typical diode is used in the test circuit and the diode is at the same T_J as the IGBT. The diode type is specified in Figure 20.
- 3. Turn-Off Energy Loss (E_{OFF}) is defined as the integral of the instantaneous power loss starting at the trailing edge of the input pulse and ending at the point where the collector current equals zero (I_{CE} = 0 A). All devices were tested per JEDEC Standard No. 24-1 Method for Measurement of Power Device Turn-Off Switching Loss. This test method produces the true total Turn-Off Energy Loss.

Typical Performance Curves Unless Otherwise Specified

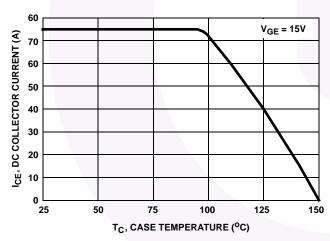


FIGURE 1. DC COLLECTOR CURRENT vs CASE TEMPERATURE

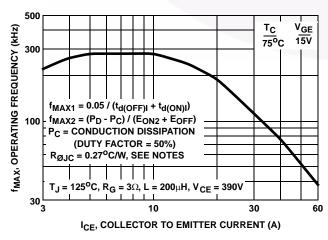


FIGURE 3. OPERATING FREQUENCY vs COLLECTOR TO EMITTER CURRENT

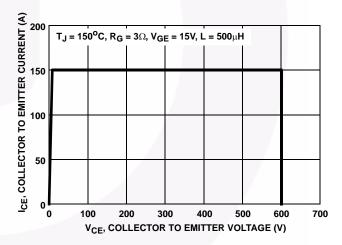


FIGURE 2. MINIMUM SWITCHING SAFE OPERATING AREA

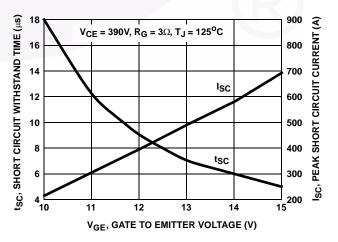


FIGURE 4. SHORT CIRCUIT WITHSTAND TIME

Typical Performance Curves Unless Otherwise Specified (Continued)

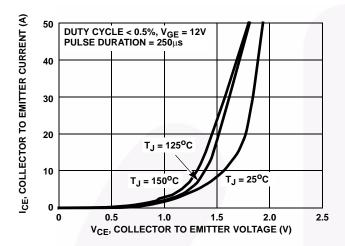


FIGURE 5. COLLECTOR TO EMITTER ON-STATE VOLTAGE

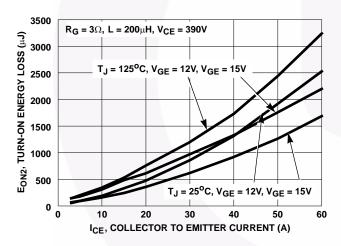


FIGURE 7. TURN-ON ENERGY LOSS vs COLLECTOR TO EMITTER CURRENT

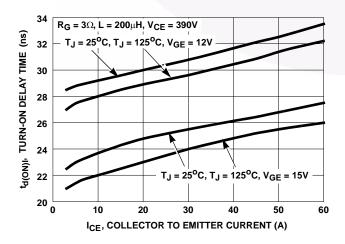


FIGURE 9. TURN-ON DELAY TIME vs COLLECTOR TO EMITTER CURRENT

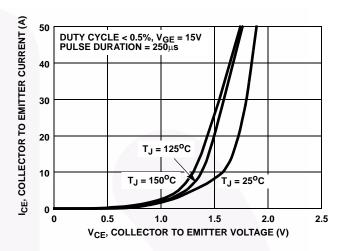


FIGURE 6. COLLECTOR TO EMITTER ON-STATE VOLTAGE

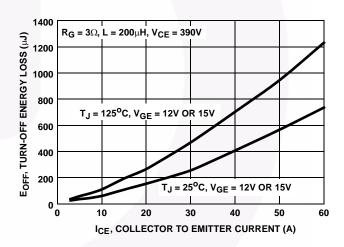


FIGURE 8. TURN-OFF ENERGY LOSS vs COLLECTOR TO EMITTER CURRENT

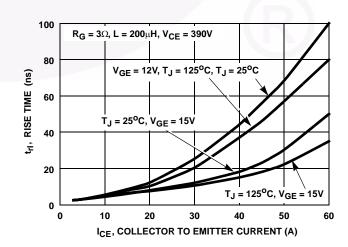


FIGURE 10. TURN-ON RISE TIME VS COLLECTOR TO EMITTER CURRENT

Typical Performance Curves Unless Otherwise Specified (Continued)

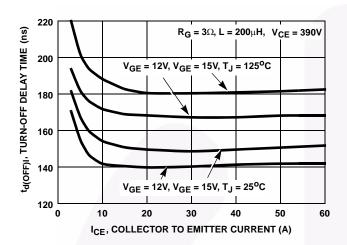


FIGURE 11. TURN-OFF DELAY TIME vs COLLECTOR TO EMITTER CURRENT

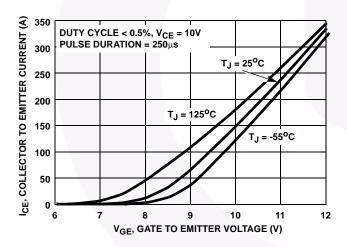


FIGURE 13. TRANSFER CHARACTERISTIC

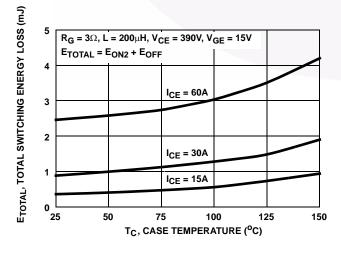


FIGURE 15. TOTAL SWITCHING LOSS vs CASE TEMPERATURE

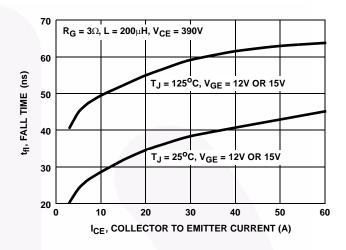


FIGURE 12. FALL TIME vs COLLECTOR TO EMITTER CURRENT

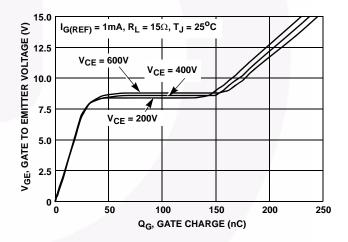


FIGURE 14. GATE CHARGE WAVEFORMS

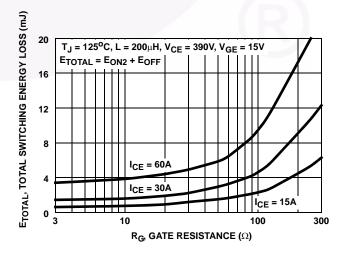
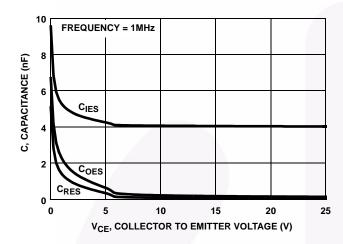


FIGURE 16. TOTAL SWITCHING LOSS vs GATE RESISTANCE

Typical Performance Curves Unless Otherwise Specified (Continued)



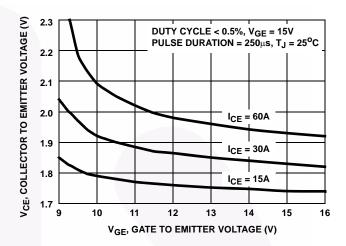


FIGURE 17. CAPACITANCE vs COLLECTOR TO EMITTER VOLTAGE

FIGURE 18. COLLECTOR TO EMITTER ON-STATE VOLTAGE vs GATE TO EMITTER VOLTAGE

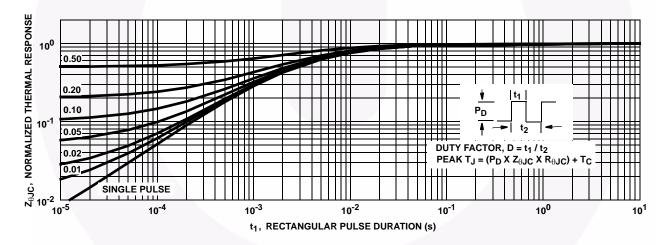


FIGURE 19. IGBT NORMALIZED TRANSIENT THERMAL RESPONSE, JUNCTION TO CASE

Test Circuit and Waveforms

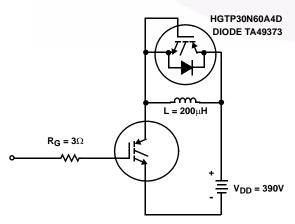


FIGURE 20. INDUCTIVE SWITCHING TEST CIRCUIT

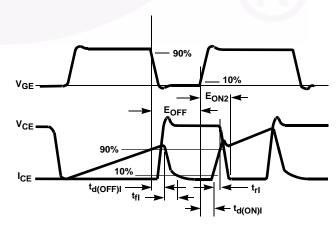


FIGURE 21. SWITCHING TEST WAVEFORMS

Handling Precautions for IGBTs

Insulated Gate Bipolar Transistors are susceptible to gate-insulation damage by the electrostatic discharge of energy through the devices. When handling these devices, care should be exercised to assure that the static charge built in the handler's body capacitance is not discharged through the device. With proper handling and application procedures, however, IGBTs are currently being extensively used in production by numerous equipment manufacturers in military, industrial and consumer applications, with virtually no damage problems due to electrostatic discharge. IGBTs can be handled safely if the following basic precautions are taken:

- Prior to assembly into a circuit, all leads should be kept shorted together either by the use of metal shorting springs or by the insertion into conductive material such as "ECCOSORBDTM LD26" or equivalent.
- When devices are removed by hand from their carriers, the hand being used should be grounded by any suitable means - for example, with a metallic wristband.
- 3. Tips of soldering irons should be grounded.
- 4. Devices should never be inserted into or removed from circuits with power on.
- Gate Voltage Rating Never exceed the gate-voltage rating of V_{GEM}. Exceeding the rated V_{GE} can result in permanent damage to the oxide layer in the gate region.
- 6. Gate Termination The gates of these devices are essentially capacitors. Circuits that leave the gate opencircuited or floating should be avoided. These conditions can result in turn-on of the device due to voltage buildup on the input capacitor due to leakage currents or pickup.
- Gate Protection These devices do not have an internal monolithic Zener diode from gate to emitter. If gate protection is required an external Zener is recommended.

Operating Frequency Information

Operating frequency information for a typical device (Figure 3) is presented as a guide for estimating device performance for a specific application. Other typical frequency vs collector current (I_{CE}) plots are possible using the information shown for a typical unit in Figures 5, 6, 7, 8, 9 and 11. The operating frequency plot (Figure 3) of a typical device shows f_{MAX1} or f_{MAX2} ; whichever is smaller at each point. The information is based on measurements of a typical device and is bounded by the maximum rated junction temperature.

 f_{MAX1} is defined by $f_{MAX1}=0.05/(t_{d(OFF)I}+t_{d(ON)I}).$ Deadtime (the denominator) has been arbitrarily held to 10% of the on-state time for a 50% duty factor. Other definitions are possible. $t_{d(OFF)I}$ and $t_{d(ON)I}$ are defined in Figure 21. Device turn-off delay can establish an additional frequency limiting condition for an application other than $T_{JM}.$

 f_{MAX2} is defined by $f_{MAX2}=(P_D-P_C)/(E_{OFF}+E_{ON2}).$ The allowable dissipation (P_D) is defined by $P_D=(T_{JM}-T_C)/R_{\theta JC}.$ The sum of device switching and conduction losses must not exceed P_D . A 50% duty factor was used (Figure 3) and the conduction losses (P_C) are approximated by $P_C=(V_{CF}\times I_{CF})/2.$

 E_{ON2} and E_{OFF} are defined in the switching waveforms shown in Figure 21. E_{ON2} is the integral of the instantaneous power loss (I_CE x V_CE) during turn-on and E_{OFF} is the integral of the instantaneous power loss (I_CE x V_CE) during turn-off. All tail losses are included in the calculation for E_{OFF} ; i.e., the collector current equals zero (I_CE = 0).

Mechanical Dimensions В 15.87 E 12.81 E φ^{3.65}/_{3.51}/_E Φ 0.254 Μ Β ΑΜ $\phi_{3.51}^{3.65}$ 5.58 E Ø 5.20 F 13.08 MIN 3 16.25 E (1.60) 3 2.66 5.56 1.17 0.254 M B AM 11.12 NOTES: UNLESS OTHERWISE SPECIFIED. A. PACKAGE REFERENCE: JEDEC TO-247, ISSUE E, VARIATION AB, DATED JUNE, 2004. B. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS. ALL DIMENSIONS ARE IN MILLIMETERS. D. DRAWING CONFORMS TO ASME Y14.5 - 1994 DOES NOT COMPLY JEDEC STANDARD VALUE NOTCH MAY BE SQUARE G. DRAWING FILENAME: MKT-TO247A03_REV03

Figure 22. TO-247 3L - TO-247, MOLDED, 3 LEAD, JEDEC VARIATION AB

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Definition of Terms

Datasheet Identification	Product Status	Definition	
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Мы молодая и активно развивающаяся компания в области поставок электронных компонентов. Мы поставляем электронные компоненты отечественного и импортного производства напрямую от производителей и с крупнейших складов мира.

Благодаря сотрудничеству с мировыми поставщиками мы осуществляем комплексные и плановые поставки широчайшего спектра электронных компонентов.

Собственная эффективная логистика и склад в обеспечивает надежную поставку продукции в точно указанные сроки по всей России.

Мы осуществляем техническую поддержку нашим клиентам и предпродажную проверку качества продукции. На все поставляемые продукты мы предоставляем гарантию.

Осуществляем поставки продукции под контролем ВП МО РФ на предприятия военно-промышленного комплекса России, а также работаем в рамках 275 ФЗ с открытием отдельных счетов в уполномоченном банке. Система менеджмента качества компании соответствует требованиям ГОСТ ISO 9001.

Минимальные сроки поставки, гибкие цены, неограниченный ассортимент и индивидуальный подход к клиентам являются основой для выстраивания долгосрочного и эффективного сотрудничества с предприятиями радиоэлектронной промышленности, предприятиями ВПК и научноисследовательскими институтами России.

С нами вы становитесь еще успешнее!

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